

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination CHAIKEN ET AL.	
		Examiner Kailash C. Srivastava	Art Unit 1657	Page 1 of 1

**U.S. PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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*	U	Rhiel et al. 2002. Nondestructive Near-Infrared Spectroscopic Measurement of Multiple Analytes in Undiluted Samples of Serum-Based Cell Culture Media. Biotechnology and Bioengineering, Volume 77, Pages 73-82.
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